

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G8 SMD CRYSTAL
SPEC. NO. (P/N)	G83270021
CUSTOMER P/N	
ISSUE DATE	Jun.16,2016
VERSION	Α

APPROVED	PREPARED	QA
Brenda	Clame	Dong Jang
APPROVED BY	CUSTOMER:	AVL Status
Please return one copy		

PSE Technology Corporation

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*RoHS Compliant

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VER. A

1-Jun-16

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
01	Jun.1,2016			New	
02	Jun.2,2016			Updated Temperature Coefficient & C0 Added Reliability	
03	Jun.15,2016			Updated Shunt Capacitance & Motional Capacitance	
А	Jun.16,2016			Release formal version	

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ELECTRICAL SPECIFICATIONS

SRe Part Number: G83270021

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 20	ppm	at 25°C ± 5°C
Load Capacitance	CL	12.5	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ. / Max.
Equivalent Series Resistance	ESR	70	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	± 0.01ppm/°C ²
Operating Temperature Range	TR	-40 to 85	°C	
Shunt Capacitance	C0	1.5	pF	Тур.
Motional Capacitance	C1	6.5	fF	Тур.
Quality Factor	Q	13	K	Min.
Aging		± 3	ppm	Max. 1st year
Storage Temperature Range		-40 to 85	°C	
Insulation Resistance		500	МΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm
2	Shear test	Apply 20N(2.04kgf) static load to the core of quartz crystal units in the direction of the arrow using a R0.5 scratch tool, then hold for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ
3	Core body strength	Apply 10N(1.02kgf) static load to the quartz crystal units center in the direction of the arrow using a R0.5 pushing tool, then hold for 10 seconds.	
4	Vibration	Frequency sweep method shall be applied as follows. Quartz crystal units shall be vibrated with the sweeping frequency from 10Hz to 55Hz and return to 10Hz in 1 minute, with 1.5mm amplitude. This vibration shall be applied for 2 hours in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-6.	
5	Shock	Quartz crystal units shall be accelerated at 9810m/s2 by 1ms pulse duration. This shock shall be applied 3 times in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-27.	

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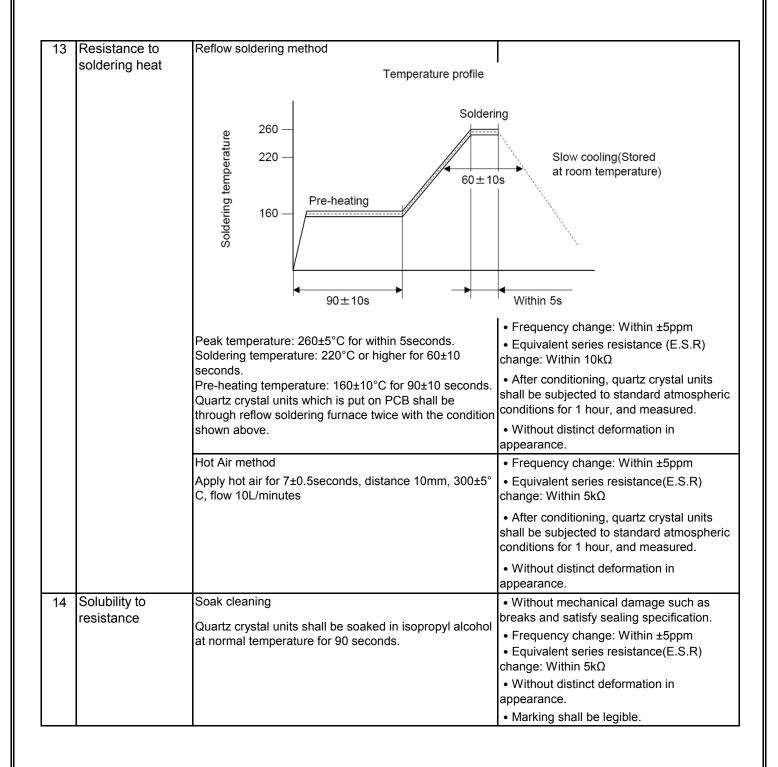
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6	Cold	Quartz crystal units shall be atmosphere for 1000 hours to JIS C 60068-2-1.	e stored in the -40±3°C . Other procedures conform	 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ
7	Dry heat	Quartz crystal units shall be atmosphere for 100 hours. JIS C 60068-2-2.		After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
8	Damp heat	Quartz crystal units shall be atmosphere with 90 to 95% hours. Other procedures co	relative humidity for 1000	
9	Change of temperature	Quartz crystal units shall be cycles of temperature chan procedures conform to JIS		
		Temperatur	e Duration	
		1 -40±3°C	30min.	
		2 Normal tempera		
		3 100±2°C	30min.	
		4 Normal tempera		
10	Sealing	Both the test methods spec Quartz crystal units shall be	cified below shall be applied.	Without repetitive leaking bubbles from
		temperature hot water for 5	-	quartz crystal units.
		Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure trate of helium gas.		• 1×10-9 Pa·m3/s or less
		rate of fiellum gas.		
11	Aging	Quartz crystal units shall be atmosphere for 720±12 hou		 Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured.
	Aging Solder-ability	Quartz crystal units shall be	urs. shall be immersed in the	 Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric
		Quartz crystal units shall be atmosphere for 720±12 hou	urs. shall be immersed in the	 Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. Minimum 95% of immersed terminal shall
		Quartz crystal units shall be atmosphere for 720±12 hou atmosphere for	shall be immersed in the onds.	 Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. Minimum 95% of immersed terminal shall
		Quartz crystal units shall be atmosphere for 720±12 hou atmosphere for	shall be immersed in the onds. Conditions	 Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. Minimum 95% of immersed terminal sha

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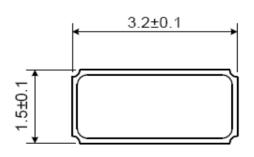
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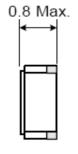
Marking

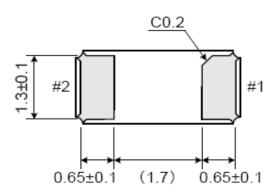




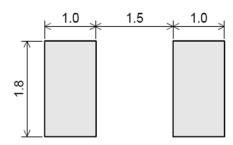
Dimensions (Units: mm)



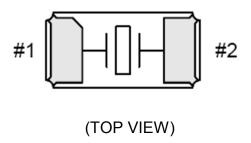




Recommended Soldering Pattern



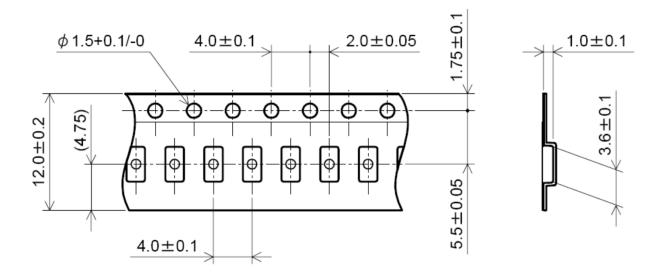
Internal connection



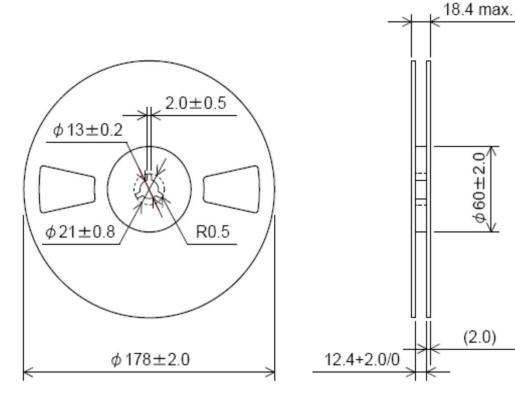
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TAPING (Units: mm)



REEL (Units: mm)



Quantity: 3000pcs / Reel

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Mouser Electronics

Authorized Distributor

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